**AMENDMENTS TO THE SPECIFICATION** 

Kindly replace the Title of the Invention with the following amended Title of the

Invention:

Trench Structure and Method of Forming the Same

Kindly amend the Abstract of the Disclosure as indicated below. A clean copy of the

amended Abstract of the Disclosure is attached at page 10 of this paper.

A trench structure of a semiconductor device includes and method for semiconductor

device isolation are disclosed, including first and second regions of a substrate having first

and second trenches, respectively, the first trench having an aspect ratio larger than that of the

second trench, a first insulation material on a bottom and sidewalls of the first trench forming

a first sub-trench in the first trench, a second insulation material completely filling the first

sub-trench, a third insulation material formed on a bottom and sidewalls of the second trench

forming a second sub-trench in the second trench, a fourth insulation material formed on a

bottom and sidewalls of the second sub-trench, and a fifth insulation material completely

filling a third sub-trench formed in the second sub-trench by the fourth insulation material.

Trench structures may be formed in high and low aspect ratio trenches in a substrate without

the generation of voids therein.

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